- **High-Speed Bus Transceivers With Parity** Generator/Checker
- Parity-Error-Fiag Open-Drain Output
- Register for Storage of the Parity-Error Flag
- Inputs are TTL-Voltage Compatible
- Flow-Through Architecture Optimizes PCB Lavout
- Center-Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

description

The 'ACT11853 is an 8-bit to 9-bit parity transceiver designed for two-way communication between data buses. When data is transmitted from the A bus to the B bus, a parity bit is generated. When data is transmitted from the B bus to the A bus with its corresponding parity bit, the ERR output will indicate whether or not an error in the B data has occurred. The output-enable inputs OEA and OEB can be used to disable the device so that the buses are effectively isolated.

A 9-bit parity generator/checker generates a parity-odd output (PARITY) and monitors the

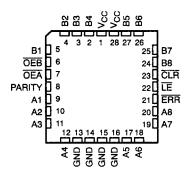
parity of the I/O ports with an open-drain parity-error flag (ERR). ERR can be either passed, sampled, stored, or cleared from the latch using the LE and CLR control inputs. The error flag register is cleared with a low pulse on the CLR input. When both OEA and OEB are low, data is transferred from the A bus to the B bus and inverted parity is generated. Inverted parity is a forced error condition that gives the designer more system diagnostic capability.

The 54ACT11853 is characterized for operation over the full military temperature range of - 55°C to 125°C. The 74ACT11853 is characterized for operation from - 40°C to 85°C.

54ACT11853 . . . JT PACKAGE 74ACT11853 . . . DW OR NT PACKAGE (TOP VIEW)

PARITY[, 0	28 OEA
A1 [2	27 OEB
A2[3	26 B1
A3[4	25 B2
A4[5	24] B3
GND[6	23 🛭 B4
GND[7	22 🕽 V _{CC}
GND[8	21 V _{CC}
GND[9	20 B5
A5[10	19🛛 B6
A6[11	18 B7
A7[12	17 B8
A8[13	16 CLR
ERR[14	15] LE

54ACT11853 . . . FK PACKAGE (TOP VIEW)



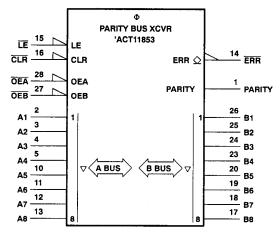
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specifications are design goels. Texas instruments reserves the rig change or discontinue these products without notice.



logic symbol†

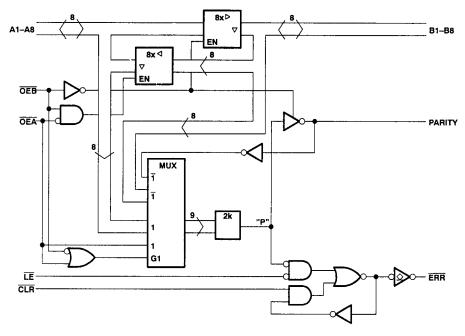


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984.



Pin numbers shown are for DW, JT, and NT packages.

logic diagram (positive logic)



FUNCTION TABLE

			INPUT	S			OUT	PUT AND I/	0		
OEB	OEA	CLR	ΪĒ	Ai Σ of H's	Bi [†] Σ of H's	А	В	PARITY	ERR‡	FUNCTION	
L.	Н	х	х	Odd Even	NA	NA	Α	L H	NA	A data to B bus and Generate Parity	
Н	L	х	L	NA	Odd Even	В	NΑ	NA	H	B Data to A Bus and Check Parity	
Н	L	Н	Н	NA	X	Х	NA	NA	NC	Store Error Flag	
Х	X	L	Н	X	×	Х	NA	NA	Н	Clear Error Flag Register	
н	н	H X X	H H L	X X L Odd H Even	х	z	z	z	NC H H L	Isolation§ (Parity check)	
L	L	х	x	Odd Even	NA	NA	Α	H	NA	A Data to B Bus and Generate Inverted Parity	

NA = Not applicable, NC = No change, X = Don't care



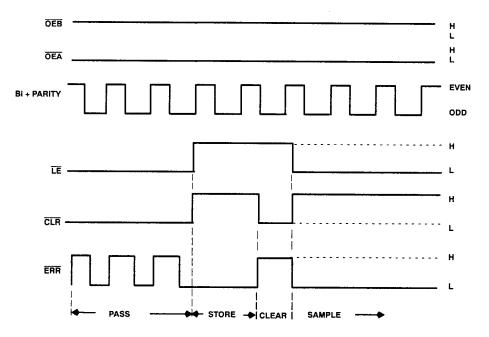
[†] Summation of high-level inputs includes PARITY along with Bi inputs.

[‡] Output states shown assume the ERR output was previously high.

 $[\]S$ In this mode, the $\overline{\sf ERR}$ output, when enabled, shows inverted parity of the A bus.

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error-flag waveforms



ERROR FLAG FUNCTION TABLE

	The state of the s										
INPUTS		INTERNAL TO DEVICE POINT "P"	OUTPUT PRE-STATE ERR _{n-1} †	OUTPUT ERR	FUNCTION						
	OLN	FOINT F	Ennn-1'	Enn							
L	L	L H	x	L H	PASS						
	.,	L	×	L							
L	н	^	ļ L	1 - 1	SAMPLE						
		н	Н	н							
Н	Ĺ	X	X	Н	CLEAR						
H	н	х	L H	L H	STORE						

[†] ERRn-1 represents the state of the ERR output before any changes at CLR, LE, or point P.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	
Input voltage range, V _I (see Note 1)	
Output voltage range, VO (see Note 1)	0.5 V to V _{CC} + 0.5 V
Input clamp current, IIK (VI < 0 or VI > VCC)	
Output clamp current, IOK (VO < 0 or VO > VCC)	
Continuous output current, I_O ($V_O = 0$ to V_{CC})	
Continuous current through V _{CC} or GND pins	
Storage temperature range	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		54	54ACT11853 74ACT11853			53		
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	٧
VIH	High-level input voltage	2			2			٧
VIL	Low-level input voltage			0.8			8.0	٧
٧ _I	Input voltage	0		Vcc	0		Vcc	٧
٧o	Output voltage	0		Vcc	0		Vcc	٧
ЮН	High-level output current			- 24			- 24	mA
lOL	Low-level output current			24			24	mA
Δt/Δν	Input transition rise or fall rate	0		10	0		10	ns/V
TA	Operating free-air temperature	- 55		125	- 40		85	°C

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TECT COMPLETONS	TEST CONDITIONS VCC MIN TYP MAY		;	54ACT	CT11853 74ACT11853				
	PARAMETER	TEST CONDITIONS	vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
		- FO A	4.5 V	4.4			4.4		4.4		
VOH VOL II IOZ ICC ΔICC §		I _{OH} = - 50 μA	5.5 V	5.4			5.4		5.4		
	All outputs except		4.5 V	3.94			3.7	•	3.8		
	ERR	I _{OH} = - 24 mA	5.5 V	4.94			4.7		4.8		٧
		I _{OH} = - 50 mA†	5.5 V				3.85				
		I _{OH} = - 75 mA [†]	5.5 V						3.85		
			4.5 V			0.1		0.1		0.1	
		IOL = 50 μA				0.1		0.1		0.1	
			4.5 V			0.36		0.5		0.44	
VOL		I _{OL} = 24 mA	5.5 V			0.36		0.5		0.44	٧
		I _{OL} = 50 mA [†]	5.5 V					1.65			1.65
		I _{OL} = 75 mA [†]	5.5 V				-,			1.65	
I _I	OEA, OEB, LE, and CLR	VI = VCC or GND	5.5 V		,	± 0.1		± 1		± 1	μА
loz	A or B ports, PARITY‡	V _O = V _{CC} or GND	5.5 V			± 0.5		± 10		± 5	μА
ICC		VI = VCC or GND, IO = 0	5.5 V			8		160		80	μА
ΔICC§		One input at 3.4 V, Other inputs at GND or VCC	5.5 V			0.9		1		1	mA
Ci	OEA, OEB, LE, and CLR	VI = VCC or GND	5 V		4.5						
Cio	A or B ports, PARITY	VO = VCC or GND	5 V		12						рF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Note 2)

			TA = 25°C		54ACT11853		74ACT11853			
			MIN MAX	MIN	MAX	MIN	MAX	UNIT		
tw	Pulse duration	LE high	5		5		5			
		LE low	5		5		5		ns	
		CLR low	5		5		5		l	
	Setup time, before LE↓	Bi and PARITY	14		14		14			
tsu	Setup time, before LET	CLR inactive	2		2		2		ns ns	
th	Hold time, Bi and PARITY after LE↓		0		Ö		0		ns	

NOTE 2: Load circuit and voltage waveforms are shown in Section 1.

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25 ^{\circ}\text{C}$

	PARAMETER		TEST CONDITIONS					
C _{pd}	Power dissipation capacitance per transceiver	Outputs enabled	A to B	to B				
			B to A	l	60	_		
		Outputs disabled	A to B	C _L = 50 pF, f = 1 MHz	28	рF		
		Outputs disabled	B to A		8	ŀ		



[‡] For I/O ports, the parameter IOZ includes the input leakage current.

[§] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V to VCC.